

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Application No. 10/683,727

Filing Date October 10, 2003

First Named Inventor Sherman

Art Unit 1762

Examiner Eric B. Fuller

Attorney Docket No. ASMMC.9CP1DV1C1

(Multiple sheets used when necessary)

SHEET 1 OF 1

DEC 27 2006

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
KMS		MÖLSÄ et al., "Deposition of Cerium Dioxide Thin Films on Silicon Substrates by Atomic Layer Epitaxy," Mat. Res. Soc. Symp., Vol. 325, 1994 Materials Research Society, pp. 341-350	

3240052  
122106

Examiner Signature /Kelly Stouffer/

Date Considered 02/28/2007

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.